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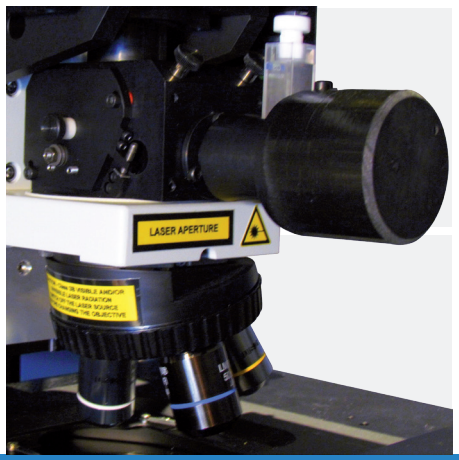
Micro Raman Accessory

Sample-Ref

Reference Sample for Environment Change Monitoring

The Sample-Ref accessory permit to apply a **correction** on the data that have been influenced by **environment changes** (room temperature, laser drift, etc.). It is very useful for fine wavenumber shift measurement (stress & strain, graphene, etc.).



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Sample-Ref

The LabRAM HR evolution equipped with this device can exhibit a very high spectral accuracy (typically better than 0.02 cm^{-1}).

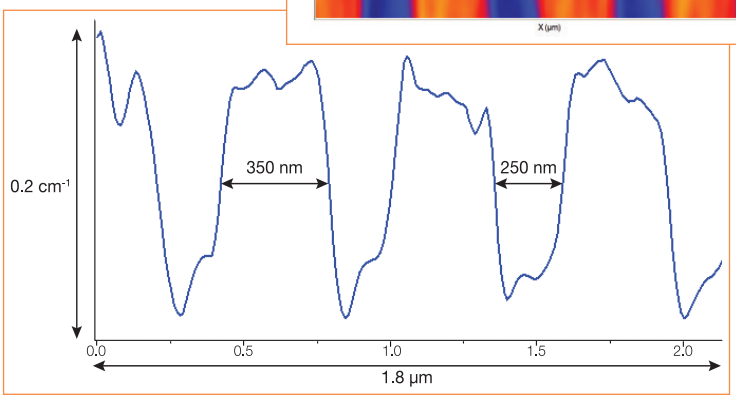
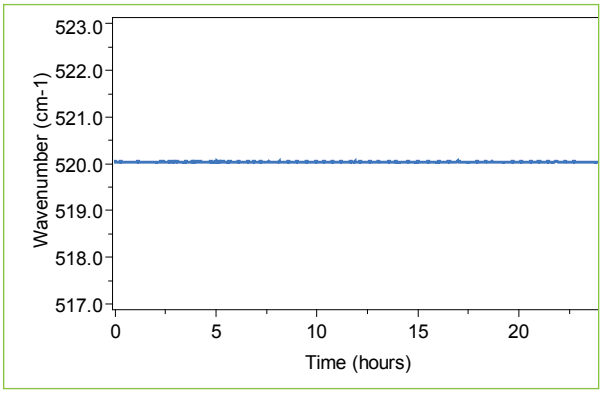


Image and profile of silicon line shift measured on strained silicon

- Spectral drift correction. A neon lamp spectra can be recorded together with the spectra of the analyzed sample allowing to correct the spectrometer spectral drift. The Raman spectrum of a reference sample can be measured simultaneously to the spectrum of the analyzed sample and permit to correct laser and spectrometer spectral drift.

- Laser power monitoring. Measuring a reference sample simultaneously with the sample of interest permits also to monitor and to correct the intensity of variation induced by the laser.

- Macro Raman. The same module can also be used as a macro Raman device.



Silicon line position measured over 24 hours using Sample-Ref

This accessory can be easily mounted on the open-space (FSM) upright microscope of the LabRAM HR Evolution.

Find out more at www.horiba.com/raman

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